



# **Affordable Rad-Hard – Impossible Dream?**

**Presented to 2008 Small Satellite Conference**



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Air Force Research Laboratory**



# Outline

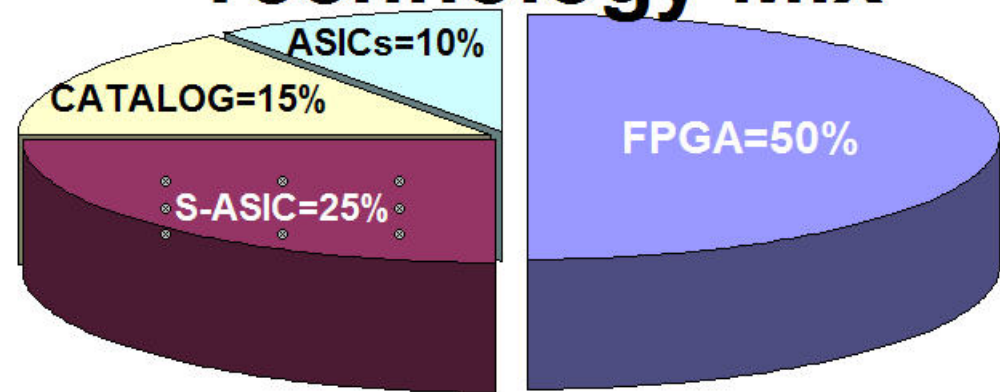
- **Vision of parts mix for future satellites**
- **FPGA – commodity parts for space**
- **Structured ASICs – nano-scale performance at low cost**
- **Catalog parts – minimally invasive process for enhanced hardness**
- **ASICs – library for hardened by design**



# Parts Mix for Future Satellites

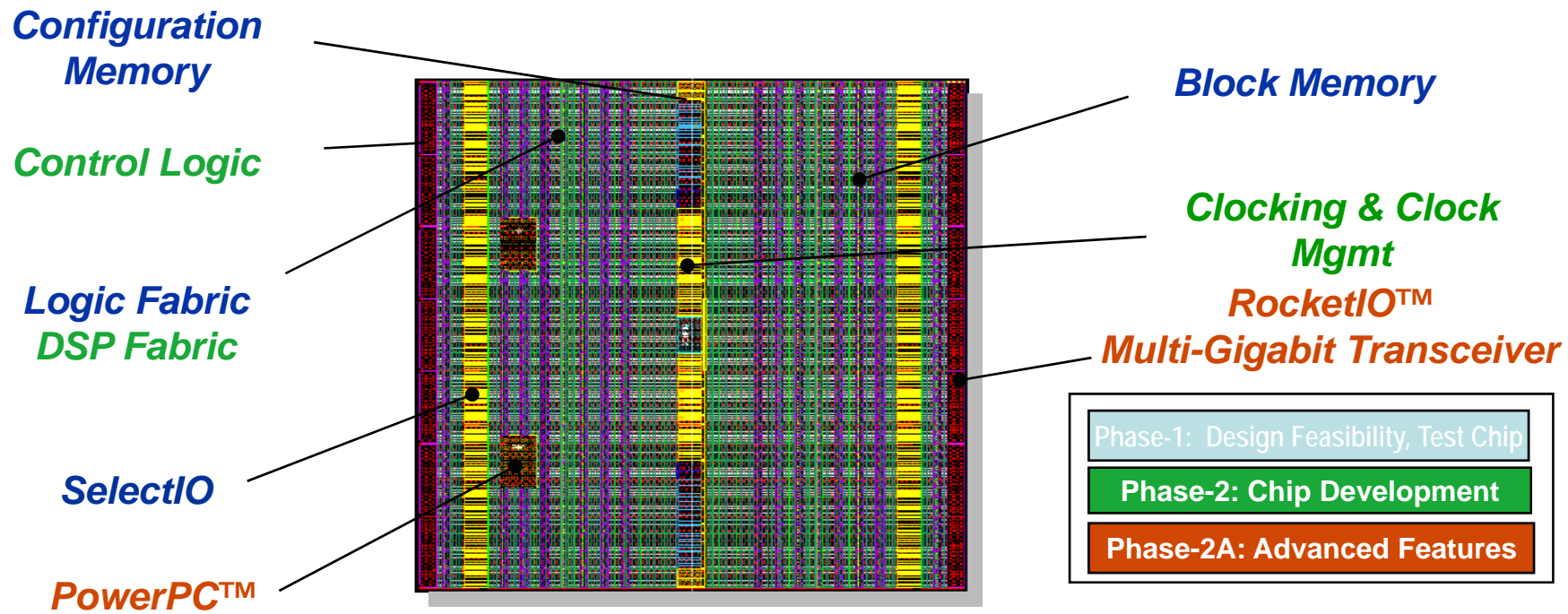
- **Tightly constrained piecepart budgets**
- **Reduced development time**
- **Decreased power allocations**
- **Increased on-board processing**
- **Standardized interfaces**

## Future Technology Mix





# SIRF VIRTEX 5 Program

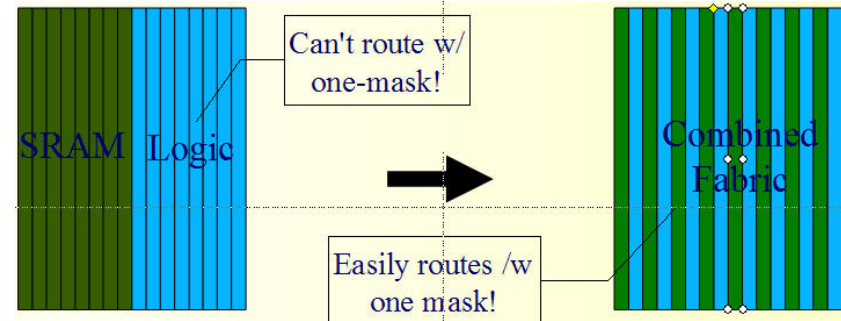
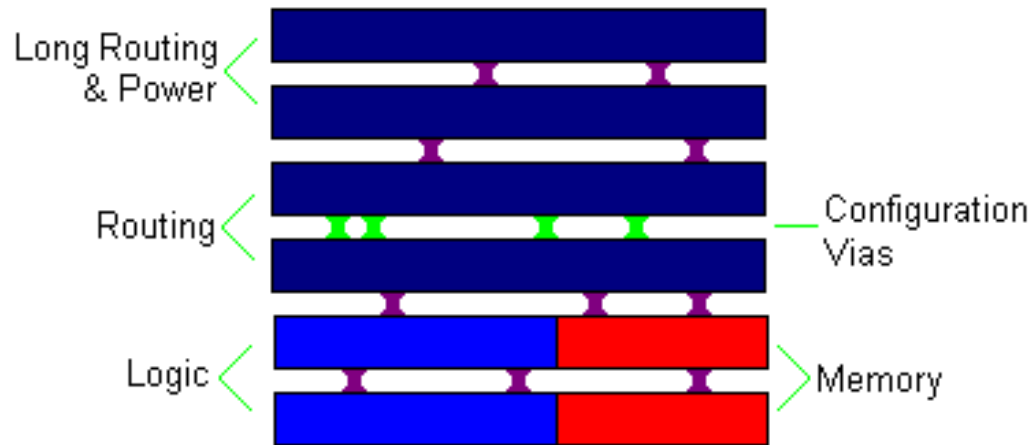


- Total Dose 300 krad(Si)
- Single Event Latchup – None
- Single Event Upset
  - 1E-2 data err/chip-day
  - 1E-4 config err/chip-day

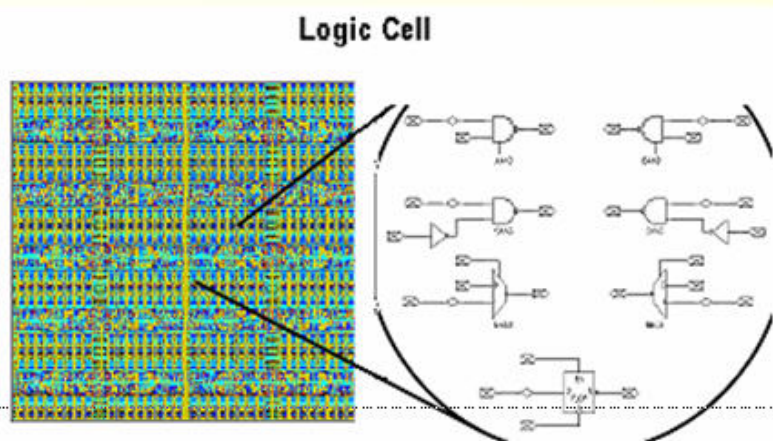
**Assumptions: AFRL rough estimates for comparable million gate applications. Typical ASIC budget is \$10M, 2 yrs; typical FPGA budget is \$2M, 6 months.**



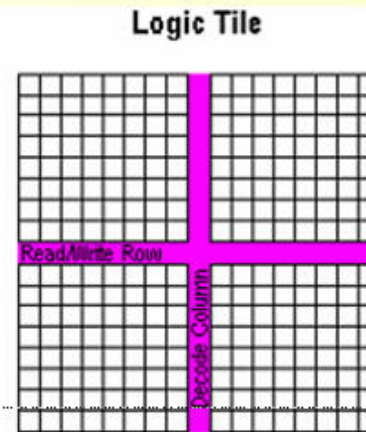
# Structured ASIC Concept



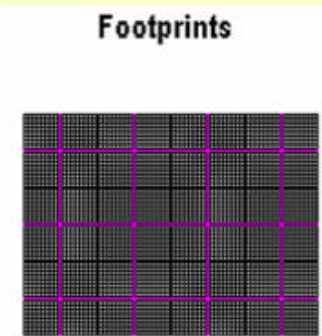
Patent 6,693,454



Logic Cells are composed of optimized simple gates and SRAM bit cells



Logic Tile made from 16x16 array of Logic Cells and a 128x[1...32]b distributed SRAM

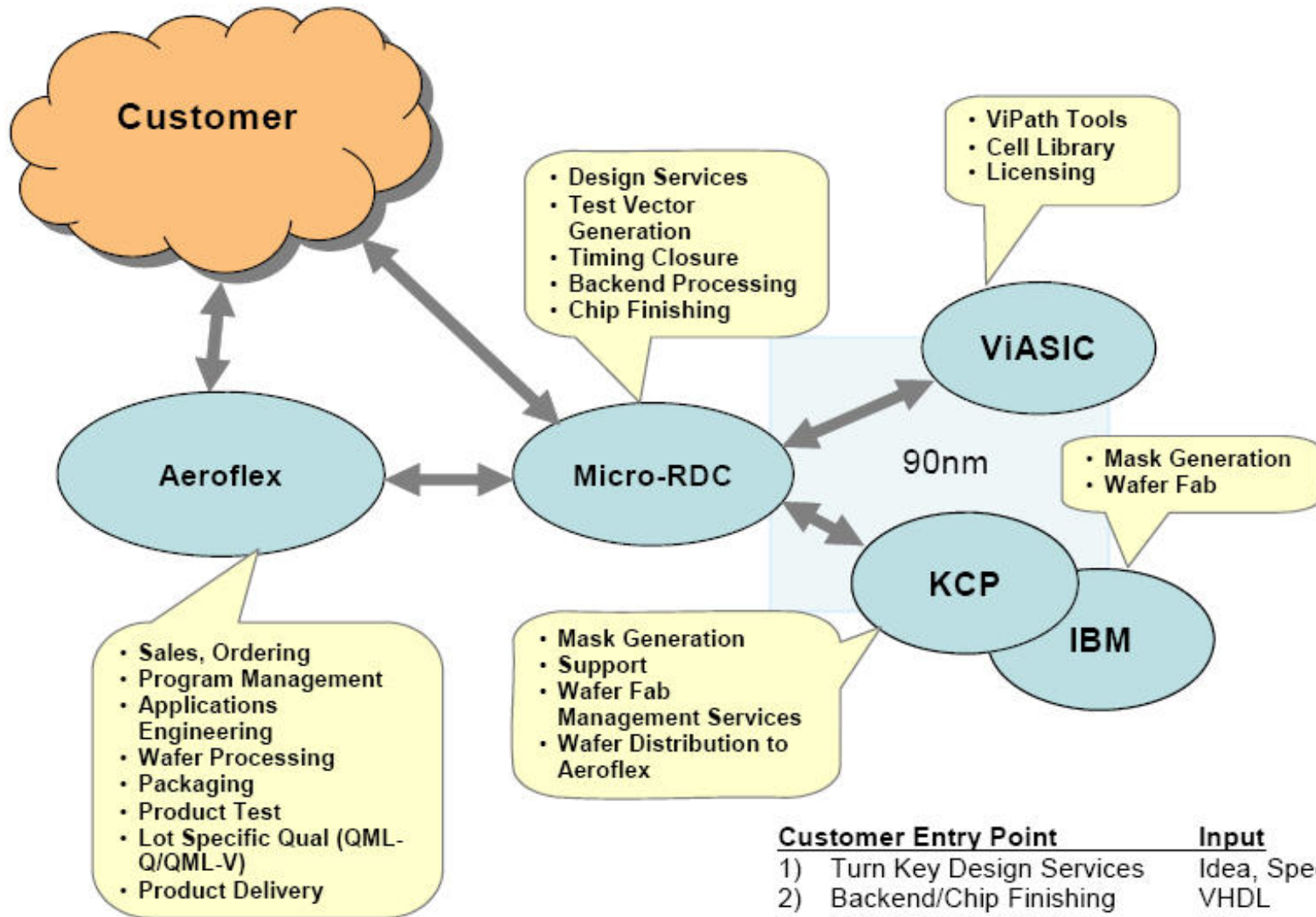


Footprints are any size array of Logic Tiles. Can be rectilinear to optimize space





# S-ASIC TEAM

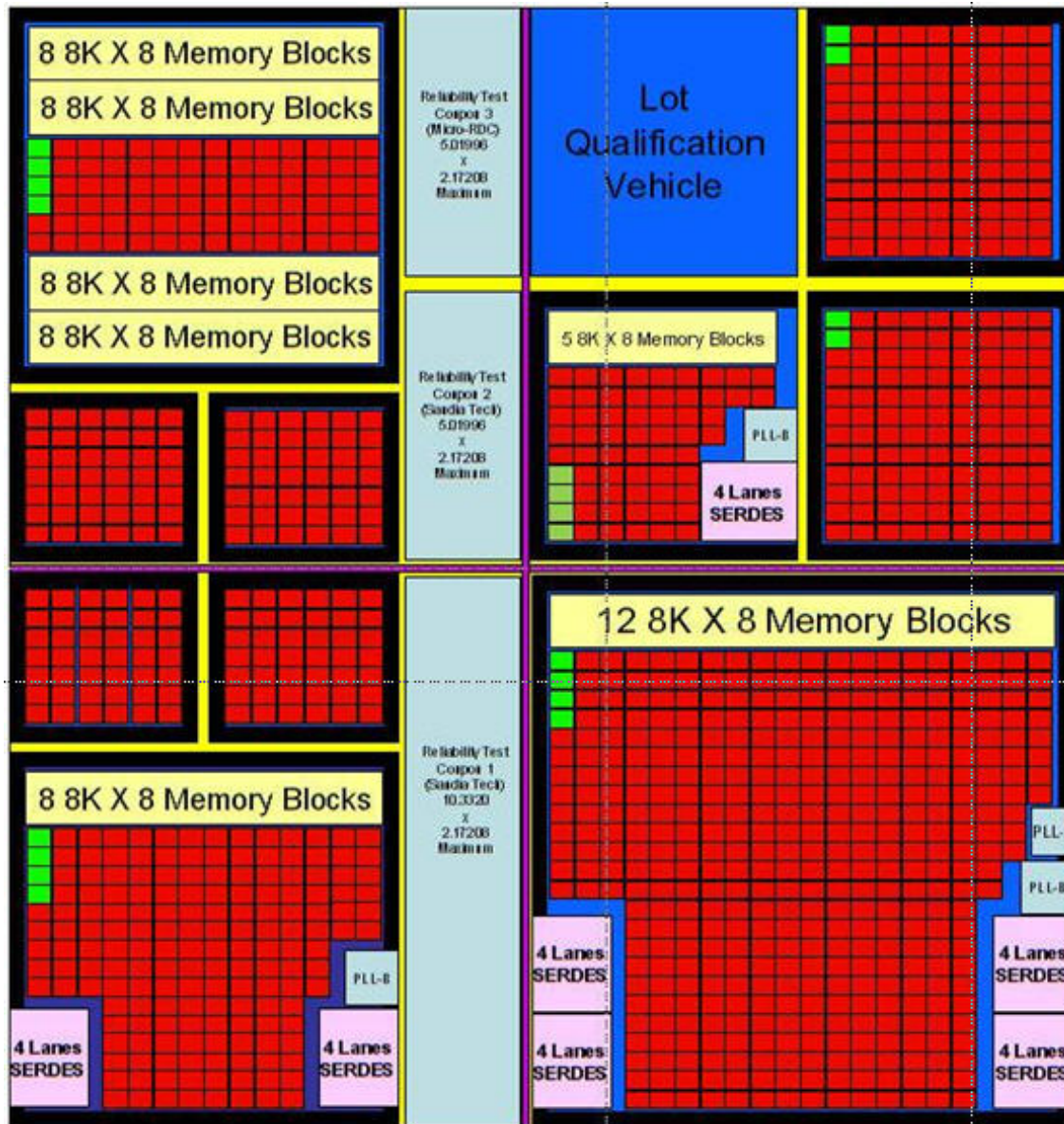


## Customer Entry Point

Customer Entry Point	Input
1) Turn Key Design Services	Idea, Spec
2) Backend/Chip Finishing	VHDL
3) ViPath Netlist Synthesis	RTL



# Reticle Floorplan



- ❑ One 10 x 10 die
  - Full feature die
- ❑ Two 7 X 7 die
  - One full feature
  - One memory heavy
- ❑ Four 5 X 5 die
  - Two full feature
  - Two logic only
  - One full feature reserved for Lot Qualification
- ❑ Four 3 X 3 die
  - Three logic only
  - One location reserved for Reliability Test Coupon



# S-ASIC Features

Die Size	Total Pads	Pwr/GND	CMOS User IO	SERDES	PLL	Block SRAM	Distributed DP SRAM	Equivalent Logic Gates	SERDES LVDS*	PLL	VROM
3 x 3	172	60	96	0	0	None	~86K Bits	~126K	No	No	None
5 x 5 A	276	112	158	0	0	None	~217K Bits	~318K	No	No	256K Bits
5 x 5 B	276	92	128	28	18	5 Blocks 8K X 8	~125K Bits	~183K	Yes (4 Lanes)	Yes	512K Bits
7 x 7 A	410	114	192	56	18	7 Blocks 8K X 8	~356K Bits	~522K	Yes (8 Lanes)	Yes	512K Bits
7 x 7 B	410	154	248	0	0	28 Blocks 8K X 8	~164K Bits	~240K	No	No	512K Bits
10 x 10	604	152	328	112	31	8 Blocks 8K X 8	~850K Bits	~1.2M	Yes (16 Lanes)	Yes	512K Bits

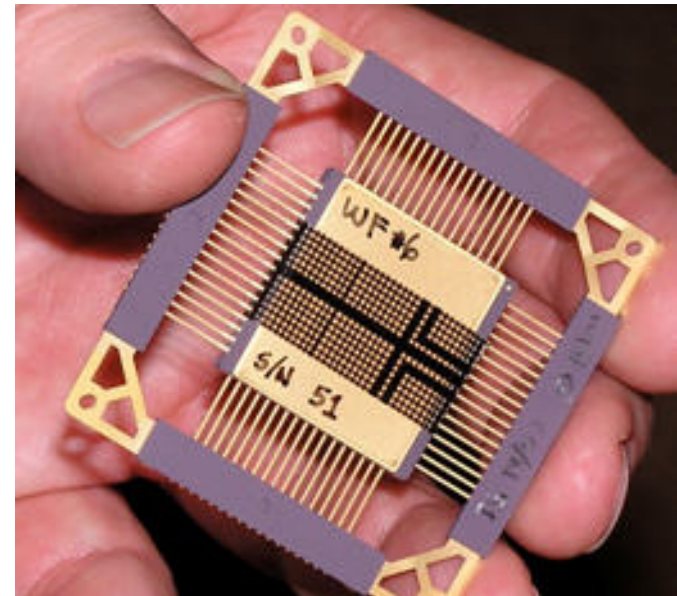
\* LVDS IO is only available if not using the SERDES lane(s).





# 16 Mbit SRAM Team

- **Silicon Space Technology**
  - Minimally Invasive Implant Technology
  - 16 Mbit Architecture
    - Silicon Design Solutions – Designers
    - DPACI – Prototype packaging
- **Texas Instruments**
  - 180 nm process
  - 12 wafers processed
  - 3 splits
    - Baseline
    - Implant A
    - Implant B
  - First pass yield 40% to 50% (573 devices)
  - Process compatible with hardening catalog parts





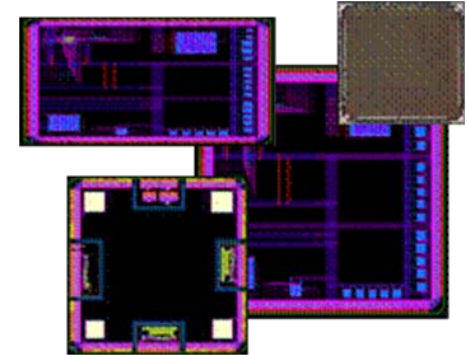
# 16 Mbit SRAM Characteristics

- **C05HA512K32 is a high performance CMOS SRAM organized as 524,288 words with 32-bit word.**
- **Configurable as Master or Slave device during package. Master device (C05HA512K32M) can initiate autonomous scrub and demand scrub cycles on Slave device (C05HA512K32S).**
- **20ns read, 10ns write maximum access time**
- **Functionally compatible with commercial 512Kx32 SRAM devices**
- **Built-in EDAC (Error Detection and Correction) to mitigate soft errors**
- **Built-in Scrub Engine for autonomous correction**
- **CMOS compatible input and output level, three state bidirectional data bus**
- **3.3 +/- 0.3V I/O, 1.8 +/- 0.15V CORE**
- **Radiation performance**
  - **Use both substrate engineering and radiation hardened by design (HBD)**
- **Packaging -- 68-lead ceramic quad flatpack (CQFP68)**



# Library for Affordable ASICs\*

- 1014 Cells - equivalent to commercial library with parameterized options for speed, power, radiation hardness. Designed and verified for IBM 9SF process.
  - Status V1 Library Status
    - Electrical, Functional, Radiation characterization complete
    - EDA views, models validated
    - Used in multiple circuit designs
    - SET generation and sensitivity characterization in work
  - DICE Status
    - V2 – Passed Go-NoGos, mitigated angular effects
    - V3 - Jan '08 Test – Used on OPERA/PDV1
    - V4 – May '08 Test



Development Step	Data included
Synthesis	<ul style="list-style-type: none"><li>• Liberty Format Files (.lib)</li><li>• Synopsys Data Base Files (.db)</li></ul>
Simulation	<ul style="list-style-type: none"><li>• Verilog simulation models</li><li>• VHDL VITAL simulation models</li><li>• Cadence schematics</li></ul>
Placement & Routing	<ul style="list-style-type: none"><li>• Cell physical geometry</li><li>• Cell frame views</li><li>• Cell timing views</li><li>• Cell power views</li><li>• Technology file</li></ul>
Verification	<ul style="list-style-type: none"><li>• Cell SPICE netlist</li><li>• Verification decks version</li></ul>
Support data	<ul style="list-style-type: none"><li>• Cell datasheets</li><li>• Models &amp; Design rules version</li></ul>

**Bottom Line: The government owns this technology and will ensure that it is made available to any and all government contractors and both Boeing and DARPA concur with this position.**

\*Cohn, L.M., 2008 Fault Tolerant Space-borne Computing Workshop



# Summary

- Affordability must be judged in terms of total system cost
  - Acquisition
  - Test
  - Application engineering
- Programs are underway to ensure the availability of reasonably priced, high performance pieceparts for space systems